

Day 1 Tuesday, May 9, 2023 Technical Breakout Sessions (each session is 35 mins presentation/Q&A + 10mins break/transit time)							
Time / Room	Salon A/B - HPD	Salon C/D - 5GMM / HSDI	Salon E - Hot Topics	Seattle - T2000	Portland-Test Methodology/DSL	Jewport Beach - Test Methodology	Santa Barbara - Test Methodology
7:50 AM	WELCOME AND EVENT HIGHLIGHTS AND KEYNOTE 1						
11:00 AM	7-HPD-V93000 Testing Of Ground Referenced Signaling At 40Gbps	5-5GMM-V93000 A Training and Demonstration Setup For Ota Testing With the Advantest V93000 Platform	4-HT-V93000 An Integrated Screening Method Algorithm For Automotive Zero-Defect Strategy	36-T2000-T2000 High Efficient Program Conversion From T2000 IPS To IPSE	1-TM-V93000 Measurement Of Impedance Curves With MBAV8 Or WSMX	65-TM-V93000 HVM Test Of UCIE-Enabled Chiplets For 2.5D and 3D Devices: the Case For A Dedicated Test Port	123-TM-V93000 An Easier Way To Support Shmoo Search Or Engineer Debugging In Production In EXA Scale
11:45 AM	30-HPD-V93000 Generic HBM2E Verification Process Thru. Smartrdi On AI/HPC Devices	13-FA-V93000 Optimized and Improved ATE Loadboard Design With EXA Scale "Stripe" Configuration	28-HT-V93000 Optimizing Vector Memory Consumption and Expediting Device Ramp With Smartest 8 Test Program Resource Profiler Tool	80-T2000-T2000 High Speed Device Interface For the T2000 Image Sensor Test Solution	128-DSL-T-V93000 Voltage Ramp Definition with Research and Analysis when Testing BMS IC	70-TM-V93000 Improving Bind and Export Times Through In-Memory Setup Generation and Protocol Access	124-TM-V93000 Using Smart-RDI To AccelerATE Analog/Mixed-Signal Test Program Validation
12:30 PM	LUNCH & EXPO						
2:00 PM	35-HPD-V93000 An Efficient Methodology To Shorten Device Performance Tuning On Serdes 112G PAM4 in AI/HPC Application	24-5GMM-V93000 A Best Practice For 5G NR MMWave Devices Test Solution In V93000 WSMM Platform	95-HT-V93000 Best Practices For Securing Your Application and Data On Cloud	85-T2000-T2000 An Evaluation Of A New External Module, Micro-Microammeter-Fronted (MMAF), For pA-Order Of Low Current Measurement Targeting Medical Devices.	6-TM-V93000 Display Port 2.0 Tx Testing on the V93000		126-TM-V93000 Utilizing DC Scale XPS256'S Background Profiling Capabilities As Effective Safety Measure In Production and Debug Tool In Engineering
2:45 PM	37-HPD-V93000 Wafer Level Stress: Current Flow Adaptive Control During Voltage Stress On AI/HPC Devices	43-5GMM-V93000 Phase Measurement Using the V93000 RF Sub-Systems	107-HT-V93000 Efficient External Communication Patterns For 93000 Smartest 8 Test Programs	96-T2000-T2000 Developing Best Tools and Library For T2000 RDK	3-TM-V93000 About the Accuracy Of Common Analog and RF Measurements	77-TM-V93000 Best Practices Of Extreme Resources Sharing Connection Solution On Automotive Loadboard Design	130-TM-V93000 Towards Native IEEE 1687 (JTAG) On ATE
3:30 PM	BREAK & EXPO						
3:50 PM	59-HPD-V93000 Implementing High Throughput Scan Test and Diagnosis With Tessent Ssn and On-Chip Compare On V93000	90-HSDI-V93000 The New Protocol Solution On Smartest 8 - Protocol Access API and Transaction Sequence View	112-HT-V93000 New Cutting-Edge Adaptive Test Analytics Applications Based On A Complete Innovative Closed-Loop Real-Time ACS Edge Analytics and Control Process	118-T2000-T2000 Using Floating Resources To Test Ldo Regulators In Pmic Devices By Halving the Number Of Instruments Used	16-TM-V93000 Smartest 8 Vacant Threads Distribution Tool	62-TM-V93000 Site Specific Protocol Aware Test With Link Scale	133-TM-V93000 Keeping Phase Alignment On High-Speed Asynchronous Serial InterFaces By Avoiding Clock Restarts
4:35 PM	58-HPD-V93000 Veczilla - Standardized V93000 HPC Projects Development Procedure	19-HSDI-V93000 An Ultra Low-Cost Generic Direct Probe Card With Cantilever Needle for V93000 WSRF RF Wafer Sort	116-HT-V93000 Test Time and Cost Reduction Using Intelligent Prediction From MI Models	142-T2000-T2000 Leverage JNI For Testprogram Development - Case Study	44-TM-V93000 Parallel Protocol TIC Support In Smartest 8	83-TM-V93000 An Integrated DUT-Board Loss Compensation Mechanism For RF Testing In High Volume Manufacturing	134-TM-V93000 High Multisite PMIC Test On EXA Scale Using XPS256 and XPS128+Hv.
5:20 PM	HAPPY HOUR & EXPO						

Time / Room	Salon A/B - HPD	Salon C/D - HSDI	Salon E - Hot Topics	Seattle - PT	Portland - Test Methodology	Jewport Beach - Test Methodology	Santa Barbara - TM/HPD/HT
7:45 AM	WELCOME, KEYNOTE 2 AND BREAK						
10:30 AM	39-HPD-V93000 BB-AP 12 Site Test Solution In V93000 EXA Scale Platform	60-HPD-V93000 A Calibration Test Solution For High Performance Computing SOC'S Tsensors	117-HT-V93000 The Profitable Low-Cost Solution For High PeRFORMANCE Ad/Da Device On Using AVI64	11-PT-V93000 Fast Vt Approach On the V93000	61-TM-V93000 A Generic Approach To Perform Wide Bandwidth Flatness Compensation	84-TM-V93000 Shmoo Results Classification Based On Image Processing	139-TM-V93000 How To Use Open Ocd With Link Scale To Reduce Time To Market Using Designs Native Tooling
11:15 AM	140-HPD-V93000 Enabling Software-Based Functional Test Through 16 Lanes PCIe Interface By V93000 Link Scale Pcie Card	94-HSDI-V93000 An Approach In Testing High Current ICs (I-Test Up To 300A) on the V93000	119-HT-V93000 Enhancing Adaptive Testing With ACS Edge and Deep Data Analytics	29-PT-V93000 Automatically Monitor and Execute Diagnostics In Parametric Test Factory Automation Environment	47-TM-V93000 Auto-Generation Of Complex RF Programs For Analysis		146-HSDI-V93000 Dmux80 Reducing Cot For High Parallel MCU Applications
12:00 PM	LUNCH & EXPO						
2:00 PM	69-HPD-V93000 Loop Back Test Solution For High Speed Serdes Testing	57-HSDI-V93000 Showcasing A Migration To Protocol Access From Protocol Aware With Flash MCU Device	120-HT-V93000 Real-Time Machine Learning Prediction At Edge (DTC & MLIE)	68-PT-V93000 Parametric Test SW Integration Of SmartRDI	54-TM-V93000 Test Solution Of Mini-Lvds InterFace Transmitter For Media Chip On the V93000 Platform	97-TM-V93000 Non-Intrusive Measurement Run Data Collection In Smartes t8 By Using Java Agent Technology	131-HT-V93000 V93000 - High Voltage Test Solution Up To 6000V
2:45 PM	98-HPD-V93000 Calibration Among Different thermal Sensor For Better thermal Management In Hpc Device	64-HSDI-V93000 Tips and Tricks To Prepare A Test Program For IP Protection Using SmartTest 8	121-HT-V93000 Reducing Development Time and Test Cost Of Wifi-7 Products Using ACS Edge As A Compute Server For Highly Complex Computations	71-PT-V93000 The Practical Applications and the Development Potential Of Waveform_Task	45-TM-V93000 An Optimized ADC&DAC Test Solution From Smartscale MCX To EXA scale WSMX	99-TM-V93000 How To Deal With Multiple Measurement Execution In One Test Suite To Reduce Overall Test Program Test Time	138-HT-V93000 Automated IC Socket Defects Detection Through Deep Learning
3:30 PM	136-HPD-V93000 High Performance Compute Devices and the Road To 2,000A	86-HSDI-V93000 Smartshell Handler Control		137-PT-V93000 Parametric Test Insights Through Dynamic Data-Driven Test Flow Execution			
4:15 PM	CLOSING AND AWARD CEREMONY						

